

MT1803

N-Channel Enhancement Mode Field Effect Transistor

Product Summary

- $V_{DS}=30V$
- $I_D=85A(T_c=25^\circ C, V_{GS}=10V)$
- $R_{DS(ON)}=3.2m\Omega @V_{GS}=10V, I_D=25A$
- $R_{DS(ON)}=3.8m\Omega @V_{GS}=4.5V, I_D=20A$

Features

- High Density Cell Design for Ultra Low On-Resistance.
- Lead free product is acquired.

Applications

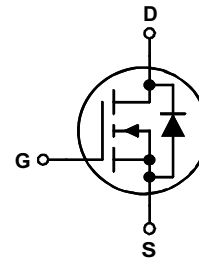
- Switching Applications.



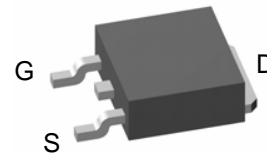
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Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



**D-PAK
TO-252-2L**

Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 12	V
I_D	Continuous Drain Current	$T_c=25^\circ C$ 85	A
I_{DM}	Pulsed Drain Current ²	200	A
I_S	Continuous Source Current (Diode Conduction) ¹	40	A
P_D	Maximum Power Dissipation ¹	$T_c=25^\circ C$ 100	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	-55 to 150	$^\circ C$

Thermal Resistance Ratings

Symbol	Parameter	Ratings	Unit
R_{thJA}	Maximum Junction-to-Ambient	52	$^\circ C/W$

Notes:

1. Surface Mounted on 1" x 1" FR4 Board, $t \leq 10$ Sec.

2. Pulse width limited by maximum junction temperature.

Electrical Characteristics (T_A=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
• Static Characteristics						
B _{VDS}	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _{DS} = 250μA	30	-	-	V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	1.0	1.6	2.0	V
I _{GSS}	Gate-Body Leakage Current	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24V, V _{GS} = 0V	-	-	50	μA
		V _{DS} = 24V, V _{GS} = 0V, T _J = 85°C	-	-	150	
R _{DS(on)}	Drain Source On State Resistance ^a	V _{GS} = 10V, I _D = 25A	-	3.2	3.9	mΩ
		V _{GS} = 4.5V, I _D = 20A	-	3.8	4.6	
V _{SD}	Diode Forward Voltage ^a	I _S = 25A, V _{GS} = 0V	-	0.5	-	V
• Dynamic Characteristics ^b						
C _{iss}	Input Capacitance	V _{DS} = 15V, V _{GS} = 0V, f= 1MHz	-	6200	-	pF
C _{oss}	Output Capacitance		-	690	-	
C _{rss}	Reverse Transfer Capacitance		-	255	-	
Q _g	Total Gate Charge	V _{DS} = 15V, V _{GS} = 10V, I _D = 25A	-	37	-	nC
Q _{gs}	Gate-Source Charge		-	9	-	
Q _{gd}	Gate-Drain Charge		-	5	-	
t _{d(on)}	Turn-On Delay Time	V _{DS} = 15V, V _{GS} = 10V I _D = 20A, R _G = 4.7Ω	-	10	-	nSec
t _r	Rise Time		-	128	-	
T _{d(off)}	Turn-Off Delay Time		-	44	-	
t _f	Fall Time		-	31	-	
R _g	Gate Resistance	V _{DS} = 0V, V _{GS} = 0V, f= 1MHz	-	1.9	-	Ω
t _{rr}	Source-Drain Reverse Recovery Time	I _S = 25A, di/dt= 100A/μs	-	32	-	nSec

Note:

a. Pulse test; pulse width ≤ 300μs, duty cycle ≤ 2%.

b. Guaranteed by design, not subject to production testing.

Typical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

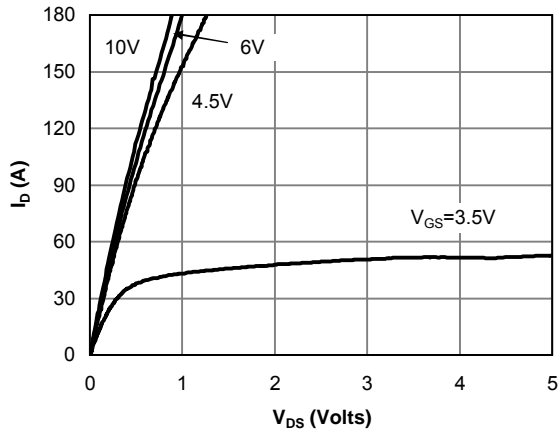


Figure 1: On-Region Characteristics

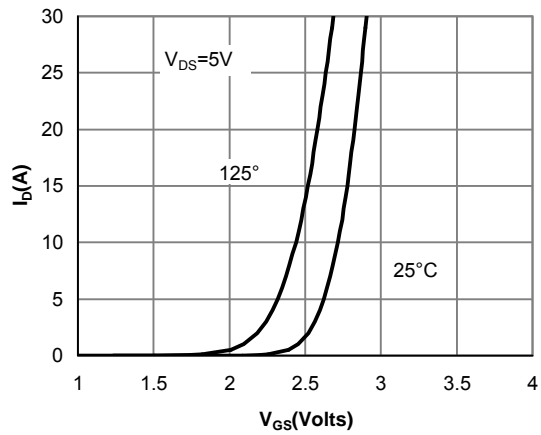


Figure 2: Transfer Characteristics

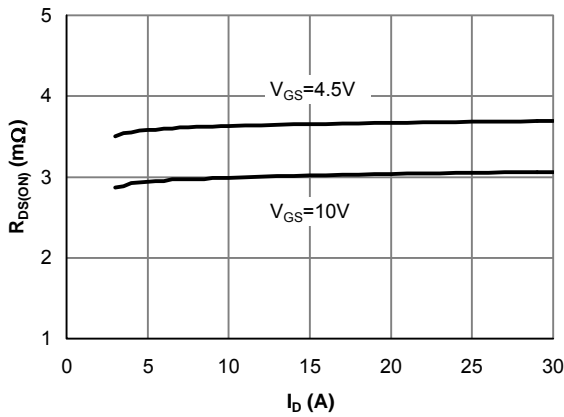


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

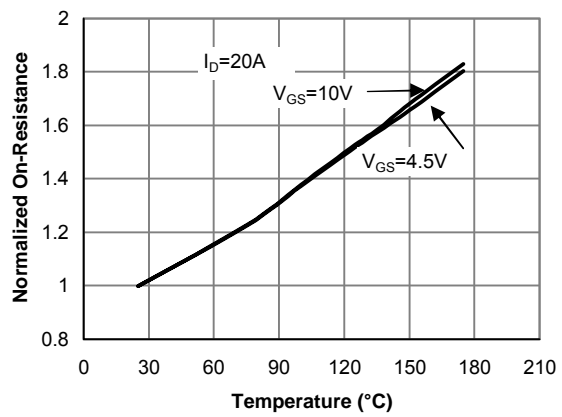


Figure 4: On-Resistance vs. Junction Temperature

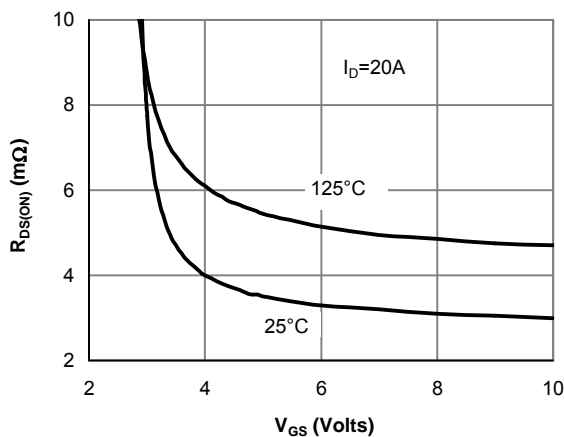


Figure 5: On-Resistance vs. Gate-Source Voltage

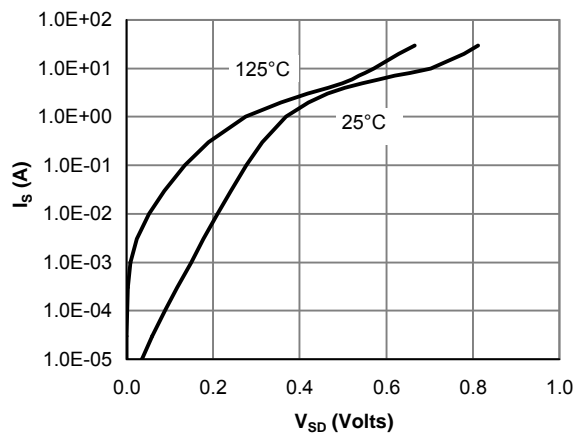


Figure 6: Body-Diode Characteristics

Typical Characteristics (Tc=25°C unless otherwise noted)

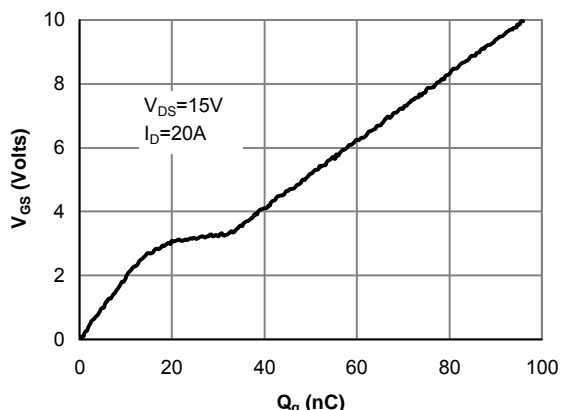


Figure 7: Gate-Charge Characteristics

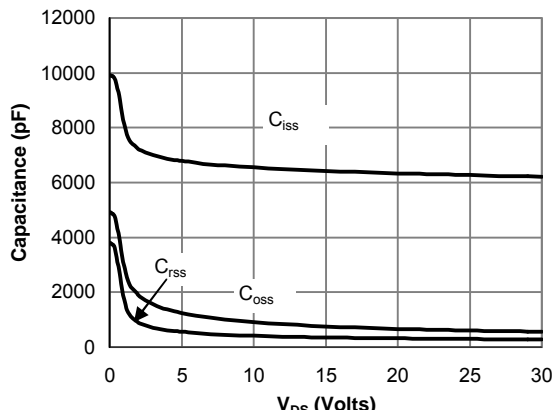


Figure 8: Capacitance Characteristics

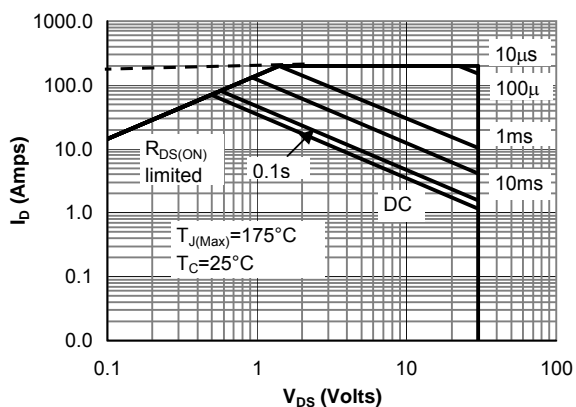


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

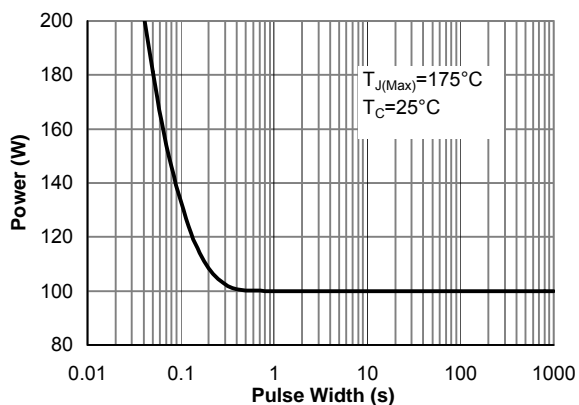


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

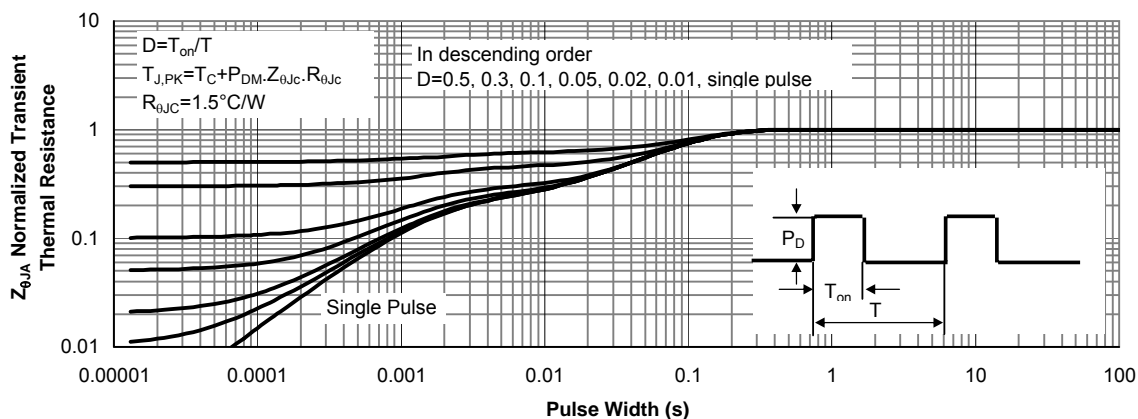


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Typical Characteristics (Tc=25°C unless otherwise noted)

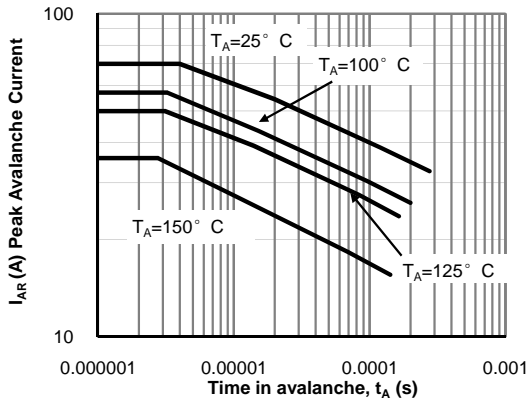


Figure 12: Single Pulse Avalanche capability (Note C)

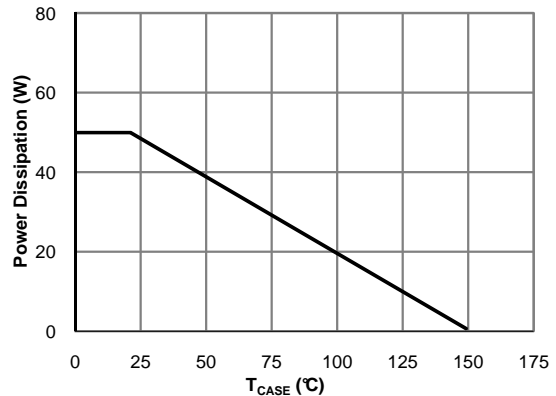


Figure 13: Power De-rating (Note F)

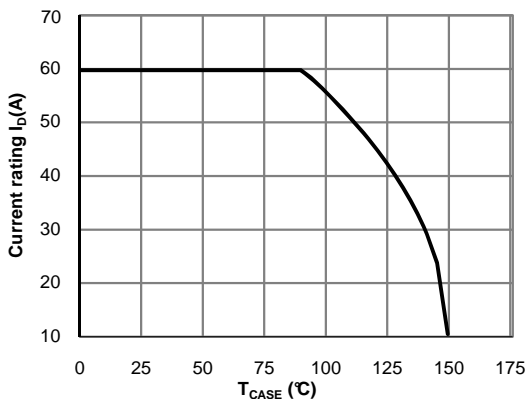


Figure 14: Current De-rating (Note F)

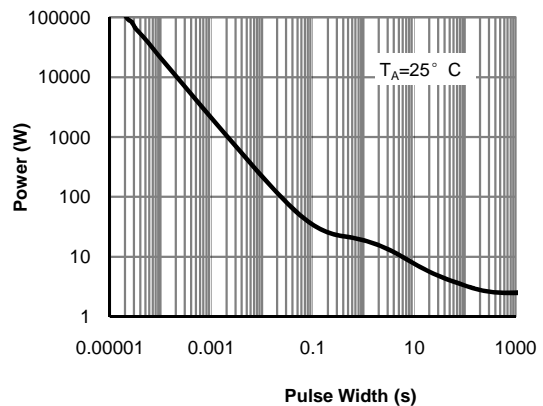


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

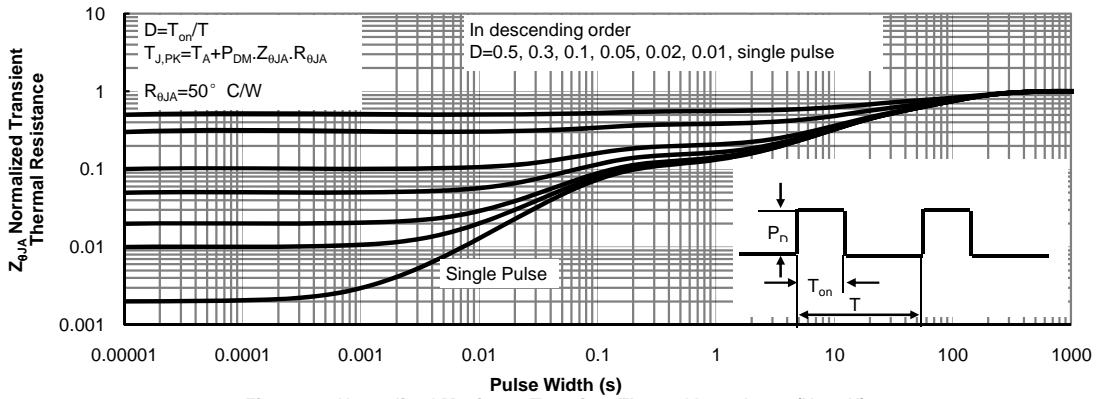
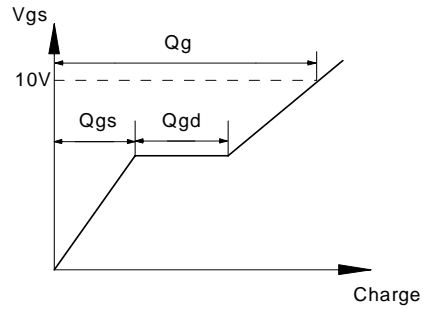
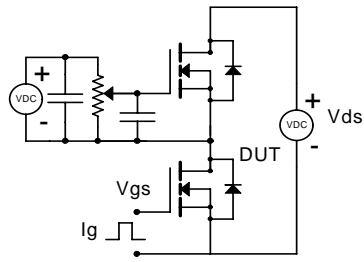
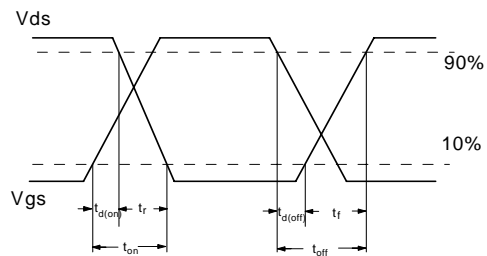
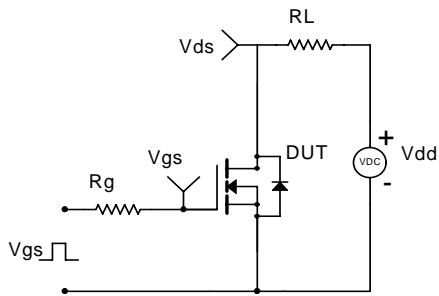


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

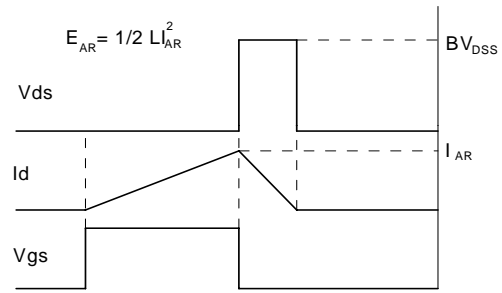
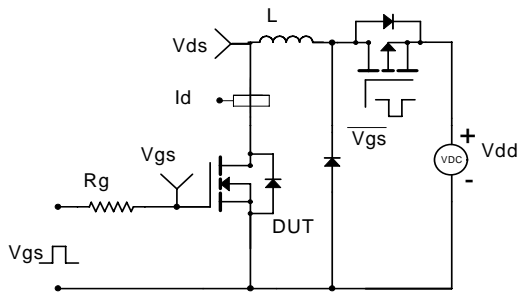
Gate Charge Test Circuit & Waveform



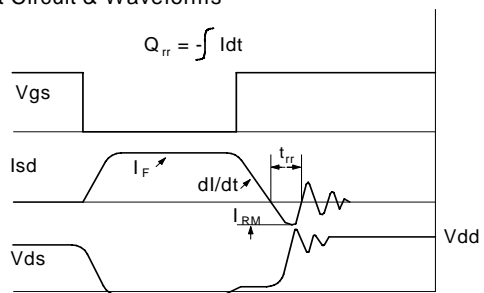
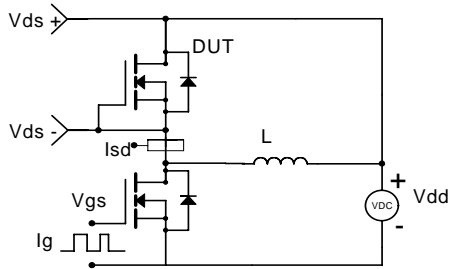
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

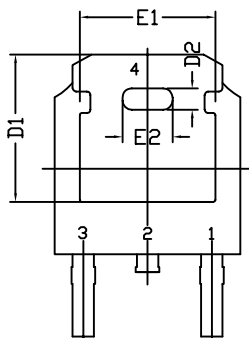
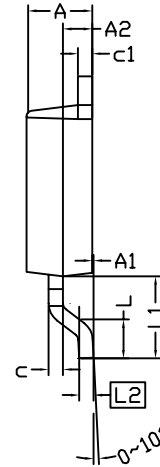
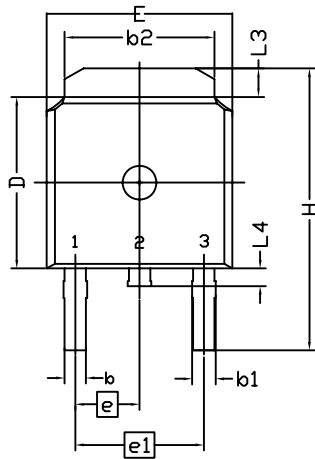


Diode Recovery Test Circuit & Waveforms

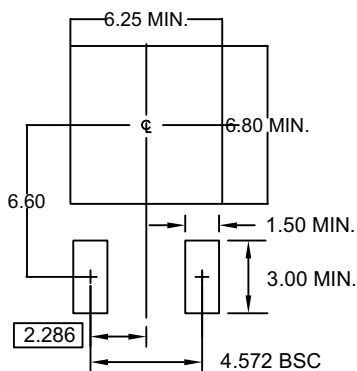


Document No.	PO-00009
Version	S

T0252(DPAK) PACKAGE OUTLINE



RECOMMENDED LAND PATTERN



UNIT: mm

NOTE

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH SHOULD BE LESS THAN 6 MILS.
2. DIMENSION L IS MEASURED IN GAUGE PLANE
3. TOLERANCE 0.10 mm UNLESS OTHERWISE SPECIFIED
4. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.
5. REFER TO JEDEC TO-252 (AA)

SYMBOL	DIMENSION IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A	2.184	2.286	2.388	0.086	0.090	0.094
A1	0.000	-----	0.127	0.000	-----	0.005
A2	0.889	1.041	1.143	0.035	0.041	0.045
b	0.635	0.762	0.889	0.025	0.030	0.035
b1	0.762	0.840	1.143	0.030	0.033	0.045
b2	4.953	5.340	5.461	0.195	0.210	0.215
c	0.450	0.508	0.610	0.018	0.020	0.024
c1	0.450	0.508	0.610	0.018	0.020	0.024
D	5.969	6.096	6.223	0.235	0.240	0.245
D1	5.210	5.249	5.380	0.205	0.207	0.212
D2	0.662	0.762	0.862	0.026	0.030	0.034
E	6.350	6.604	6.731	0.250	0.260	0.265
E1	4.318	4.826	4.901	0.170	0.190	0.193
E2	1.678	1.778	1.878	0.066	0.070	0.074
e	2.286 BSC			0.090 BSC		
e1	4.572 BSC			0.180 BSC		
H	9.398	10.033	10.414	0.370	0.395	0.410
L	1.270	1.520	2.032	0.050	0.060	0.080
L1	2.921 REF.			0.115REF.		
L2	0.408	0.508	0.608	0.016	0.020	0.024
L3	0.889	1.016	1.270	0.035	0.040	0.050
L4	0.635	-----	1.016	0.025	-----	0.040

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